Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/661,618	LIN, WEI CHENG	
Examiner	Art Unit	
Rita Leykin	2837	

Rita Leykin

SEARCHED						
Class	Subclass	Date	Examiner			
318	638	5/27/2006	R.L.			
	560					
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INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
318	638	5/27/2006	R.L.			
	560					
EA	ST	5/27/2006	R.L.			

SEARCH NO (INCLUDING SEARCH	TES I STRATEGY)
	DATE	EXMR
USPAT, DERWENT, EPO, JPO USPGPUB	5/27/2006	R.L.